

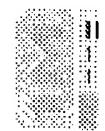
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```
vernier<paragraph>
(decompression<or>decompressed
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s)<and>event
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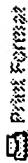
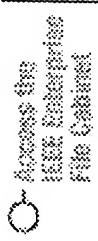
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<b>2</b>	X		US 6532561 B1	20030311		Event based semiconductor test system	714/738
<b>3</b>	X		US 6226765 B1	20010501	14	Event based test system data memory compression	714/718
<b>4</b>	X		WO 2004008157 A2	20040122	76	EVENT PIPELINE AND SUMMING METHOD AND APPARATUS FOR EVENT BASED TEST SYSTEM	
<b>5</b>	X		WO 2004008157 A	20040122		Event pipeline and vernier summing apparatus for event based semiconductor test system, has pipelines incorporated in event vernier summing logic for processing event vernier data in parallel	

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<b>1</b>	22478							
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